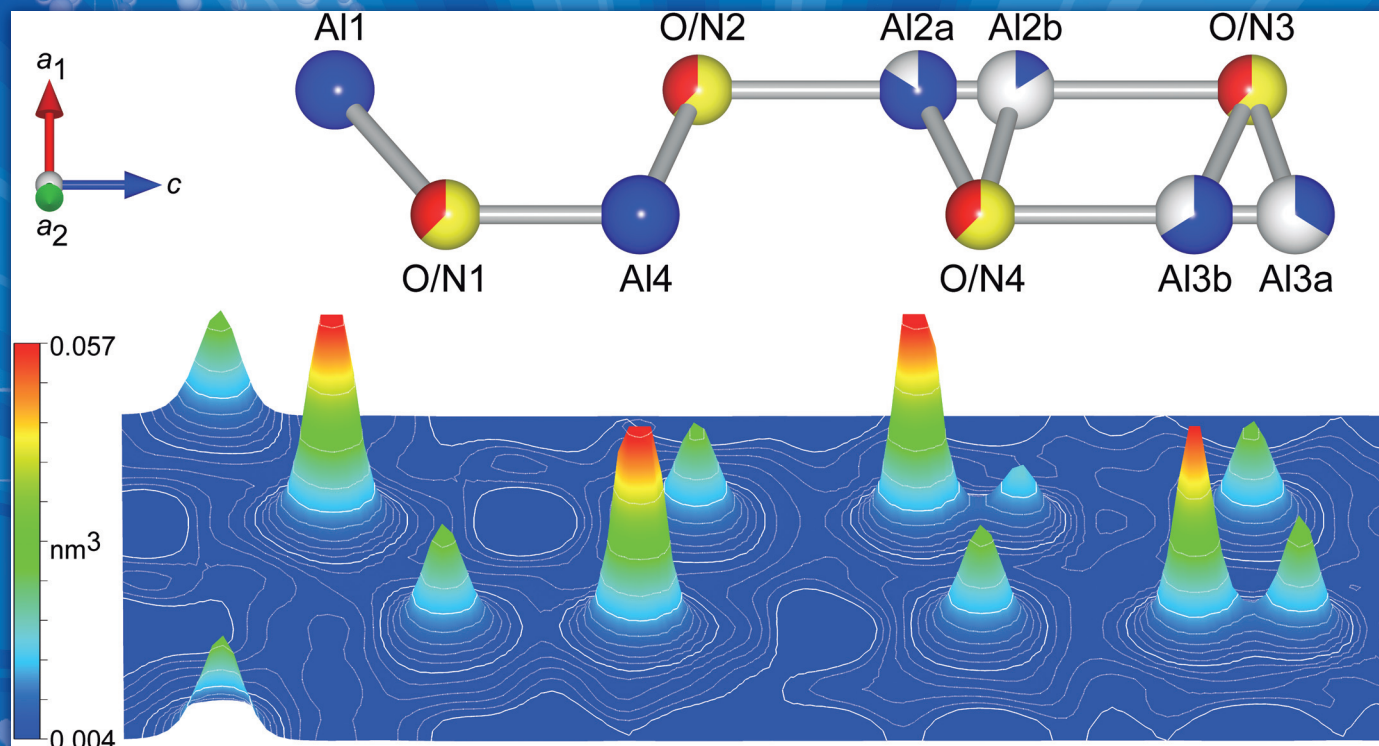
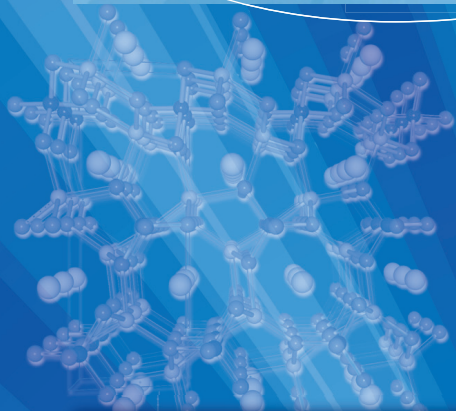


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# Powder Diffraction

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## Editor-in-Chief

Ting C. Huang  
Emeritus, IBM Almaden  
9 Fl., #61  
Sec. 1, Ao-Ho Road  
Taipei, Taiwan  
tinghuang@tinghuang.com

## Managing Editor

Nicole M. Ernst Boris  
International Centre for Diffraction Data  
12 Campus Boulevard  
Newtown Square, Pennsylvania 19073-3273, U.S.A.  
boris@icdd.com

## Editor for New Diffraction Data

Dr. Soorya Kabekkodu  
International Centre for Diffraction Data  
12 Campus Boulevard  
Newtown Square, Pennsylvania 19073-3273, U.S.A.  
kabekkodu@icdd.com

## Editors

Xiaolong Chen  
Institute of Physics  
Chinese Academy of Sciences  
No. 8 Nanshanjie, Zhongguancun, Haidian District,  
Beijing 100190,  
China  
xlchen@aphy.iphy.ac.cn

José Miguel Delgado  
Universidad de Los Andes  
Facultad de Ciencias  
Departamento de Química  
Lab de Cristalografía  
Mérida 5101  
Venezuela  
miguel@ula.ve

Norberto Masciocchi  
Università dell'Insubria  
Dipartimento di Scienza e Alta Tecnologia  
via Valleggio 11  
Como 22100  
Italy  
norberto.masciocchi@uninsubria.it

## Editors for Crystallography Education

James Kaduk  
Analytical Science Research Services  
Poly Crystallography Inc.  
423 East Chicago Avenue  
Naperville, Illinois 60540-5407, U.S.A.  
Kaduk@polycrystallography.com

Brian H. Toby  
Argonne National Laboratory  
Advanced Photon Source  
9700 S. Cass Ave., Bldg. 433/D003,  
Argonne, Illinois 60439-4856, U.S.A.  
brian.toby@anl.gov

## International Reports Editor

Winnie Wong-Ng  
National Institute of Standards and Technology  
100 Bureau Drive, Mail Stop 8520  
Gaithersburg, Maryland 20899-8520, U.S.A.  
winnie.wong-ng@nist.gov

## Calendar of Meetings and Workshops Editor

Gang Wang  
Institute of Physics  
Chinese Academy of Sciences  
No. 8 Nanshanjie, Zhongguancun, Haidian District,  
Beijing 100190,  
China  
gangwang@aphy.iphy.ac.cn

On the Cover: Figure 5. A bird's eye view of electron densities up to 50% ( $0.057 \text{ nm}^{-3}$ ) of the maximum on the plane parallel to (110) (lower part) with the corresponding atomic arrangements (upper part). (Courtesy of: Koichiro Fukuda, Toru Asaka, Tatsunari Kudo, Hiroki Banno, Shiro Funahashi, and Naoto Hirotsaki).

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